

Photointerrupters(Reflective)

KODENSHI

SG - 105F

The SG - 105F reflective sensor combines a GaAs IRED with a high - sensitivity phototransistor in a super - mini package, reducing installation space.

FEATURES

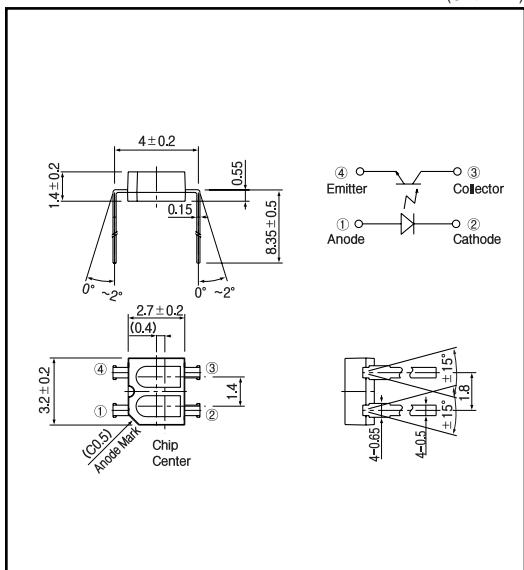
- Compact
- High performance
- High - speed response
- Easy to mount on P.C.B.
- Widely applicable

APPLICATIONS

- Timing sensors
- Edge sensors
- Micro floppy disk drives
- Level sensors of liquid

DIMENSIONS

(Unit : mm)



MAXIMUM RATINGS

(Ta=25 °C)

	Item	Symbol	Rating	Unit
Input	Power dissipation	P _D	75	mW
	Reverse voltage	V _R	5	V
	Forward current	I _F	50	mA
	Pulse forward current ¹⁾	I _{FP}	1	A
Output	Collector power dissipation	P _C	50	mW
	Collector current	I _C	20	mA
	C - E voltage	V _{CEO}	30	V
	E - C voltage	V _{ECO}	3	V
Operating temp.		Topr.	- 20 ~ +85	
Storage temp.		Tstg	- 30 ~ +100	
Soldering temp. ²⁾		Tsol.	240	

¹⁾1. t w 100 μsec. period : T=10msec.

²⁾ For MAX. 5 seconds at the position of 2mm from the package

ELECTRO-OPTICAL CHARACTERISTICS

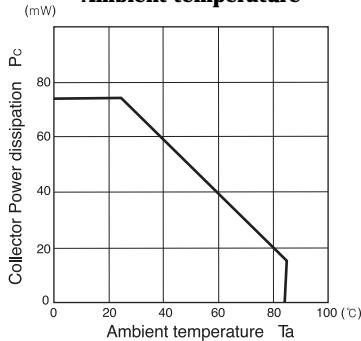
(Ta=25 °C)

	Item	Symbol	Conditions	Min.	Typ.	Max.	Unit.
Input	Forward voltage	V _F	I _F =10mA			1.3	V
	Reverse current	I _R	V _R =5V			10	μA
	Peak wavelength	λ			940		nm
Output	Collector dark current	I _{CEO}	V _{CE} =10V			0.2	μA
	Ligh current	I _L	V _{CE} =5V, I _F =10mA	90			μA
Leakage current		I _{CEO}	V _{CE} =5V, I _F =10mA			0.2	μA
Switching speeds	Rise time	t _r	V _{CC} =2V, I _F =100μA		30		μsec.
	Fall time	t _f	R _L =1K		25		μsec.

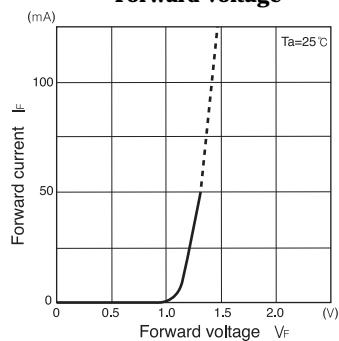
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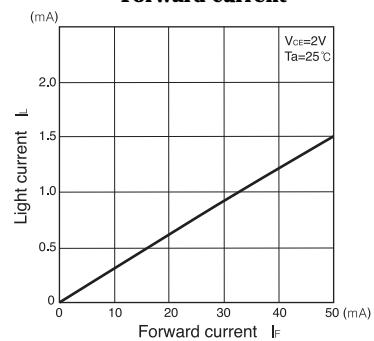
**Collector power dissipation Vs.
Ambient temperature**



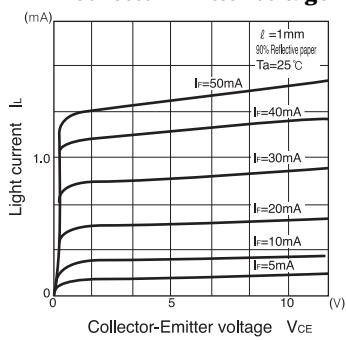
**Forward current Vs.
Forward voltage**



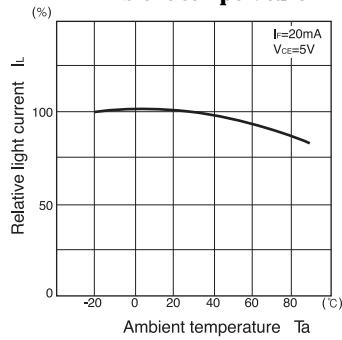
**Light current Vs.
Forward current**



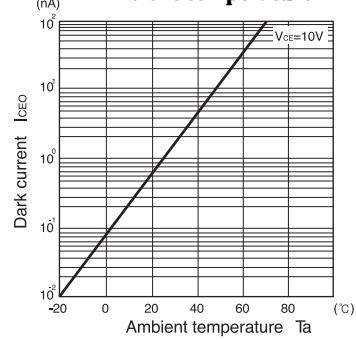
**Light current Vs.
Collector-Emitter voltage**



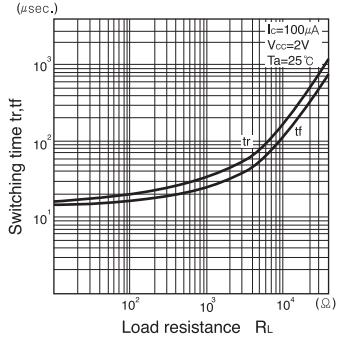
**Relative light current Vs.
Ambient temperature**



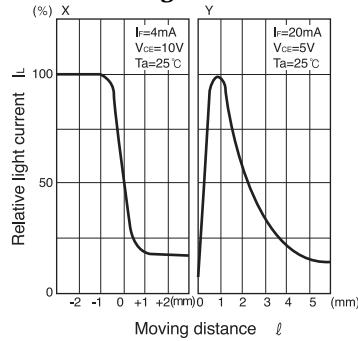
**Dark current Vs.
Ambient temperature**



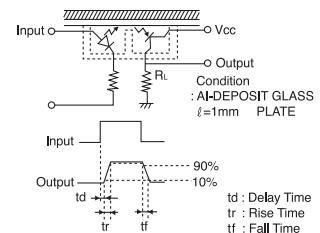
**Switching time Vs.
Load resistance**



**Relative light current Vs.
Moving distance**



Switching time measurement circuit



Method of measuring position characteristic

